

**Notice of References Cited**

Application/Control No.

10/670,523

Applicant(s)/Patent Under  
Reexamination  
IBUKA ET AL.

Examiner

TAN X. DINH

Art Unit

2627

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,218,740 B1	05-2007	Kowaki, Hiroshi	381/18
	B	US-			
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	D	US-			
	E	US-			
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	K	US-			
	L	US-			
	M	US-			

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